

Notice of References Cited	Application/Control No. 10/729,504		Applicant(s)/Patent Under Reexamination KWON, OH-KYONG	
	Examiner Kimnhung Nguyen		Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,686,699	02-2004	Yumoto, Akira	315/169.3
*	B	US-7,019,717	03-2006	Yumoto et al.	345/76
*	C	US-6,806,857	10-2004	Sempel et al.	345/92
*	D	US-2003/0011584	01-2003	Azami et al.	345/204
*	E	US-6,847,171	01-2005	Tam, Simon	315/169.3
*	F	US-6,670,773	12-2003	Nakamura et al.	315/169.3
*	G	US-5,952,789	09-1999	Stewart et al.	315/169.4
*	H	US-6,580,408	06-2003	Bae et al.	345/76
*	I	US-2004/0056604	03-2004	Shih et al.	315/169.2
*	J	US-2002/0196212	12-2002	Nishitoba et al.	345/76
*	K	US-2003/0178946	09-2003	Nakamura et al.	315/169.3
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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